


# Seminar on System-on-a-Chip (SoC) for Testing Digital Integrated Circuit (IC)

Wednesday, December 14, 11:30 A.M. Seminar Room, 1st Floor, Civil Engineering Building.

IC testing is now a burning issue in the semiconductor industry. Multi-million transistors are being integrated on a single chip. With the increase of such integration densities and complexities, problems associated with the testing of ICs have become much more complex and acute. The cost of testing has become a major portion of the total cost of an electronic product. It is predicted in a survey that it will soon cost more to test a transistor than to make it if the trend of increasing testing cost is maintained.



Dr. Mohd. Liakot Ali, Asst. Prof., IICT, BUET will present a seminar on the above issue to find an economic and reliable solution of this problem. In this seminar, Design and Development of an IC Tester using SoC technology will be presented. All of you are cordially invited.

Organized by IICT